



HIGH DENSITY MOUNTING HIGH VOLTAGE DARLINGTON OPTICALLY COUPLED ISOLATORS



APPROVALS

- UL recognised, File No. E91231

DESCRIPTION

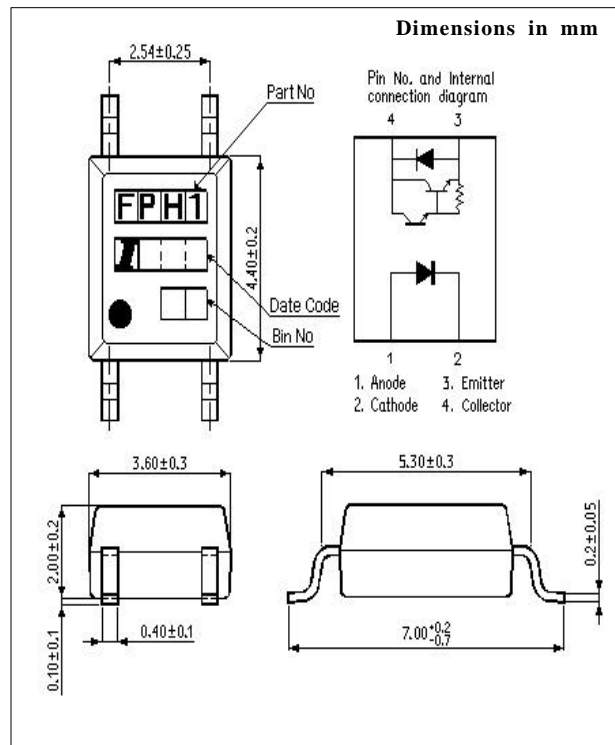
The IS2732-1 is an optically coupled isolator consisting of an infrared light emitting diode and a high voltage NPN silicon photo darlington which has an integral base-emitter resistor to optimise switching speed and elevated temperature characteristics in a space efficient dual in line plastic package.

FEATURES

- Marked as FPH1.
- Current Transfer Ratio MIN. 1000%
- High collector-emitter voltage, $V_{ce0}=300V$
- Isolation Voltage ($3.75kV_{RMS}, 5.3kV_{PK}$)
- All electrical parameters 100% tested
- Drop in replacement for NEC PS2732-1

APPLICATIONS

- Computer terminals
- Industrial systems controllers
- Measuring instruments
- Signal transmission between systems of different potentials and impedances



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ABSOLUTE MAXIMUM RATINGS
(25°C unless otherwise specified)

Storage Temperature _____ -55°C to +150°C
 Operating Temperature _____ -55°C to +100°C
 Lead Soldering Temperature
 (1/16 inch (1.6mm) from case for 10 secs) 260°C

INPUT DIODE

Forward Current _____ 50mA
 Reverse Voltage _____ 6V
 Power Dissipation _____ 70mW

OUTPUT TRANSISTOR

Collector-emitter Voltage BV_{CEO} _____ 300V
 Emitter-collector Voltage BV_{ECO} _____ 0.1V
 Collector Current _____ 150mA
 Power Dissipation _____ 150mW

POWER DISSIPATION

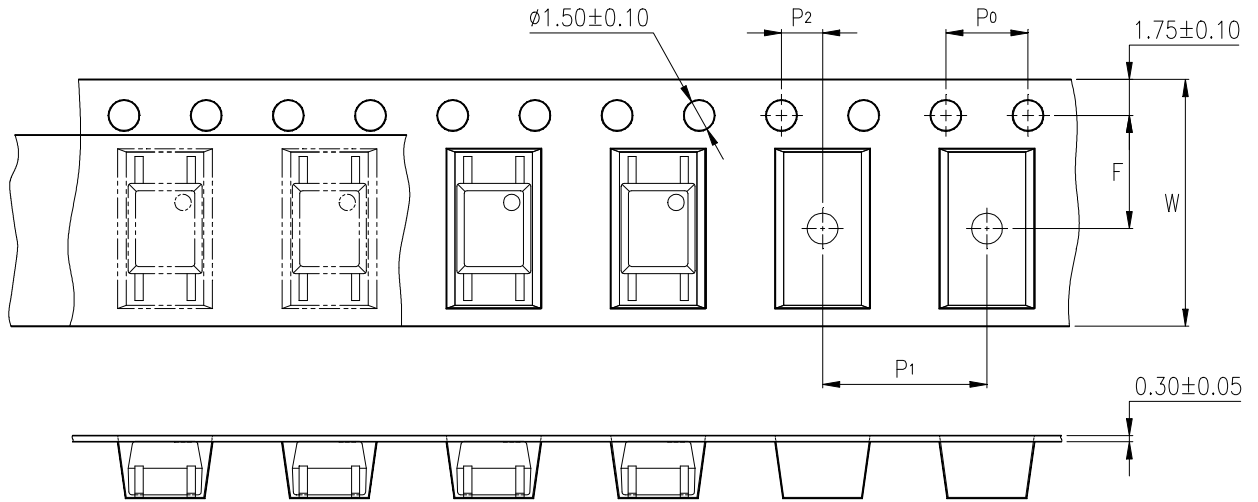
Total Power Dissipation _____ 170mW
 (derate linearly 2.26mW/°C above 25°C)

ELECTRICAL CHARACTERISTICS ($T_A = 25^\circ\text{C}$ Unless otherwise noted)

PARAMETER		MIN	TYP	MAX	UNITS	TEST CONDITION
Input	Forward Voltage (V_F)		1.2	1.4	V	$I_F = 10\text{mA}$
	Reverse Current (I_R)			10	μA	$V_R = 4\text{V}$
Output	Collector-emitter Breakdown (BV_{CEO})	300			V	$I_C = 0.1\text{mA}$
	Emitter-collector Breakdown (BV_{ECO})	0.1			V	$I_E = 10\mu\text{A}$
	Collector-emitter Dark Current (I_{CEO})			200	nA	$V_{CE} = 200\text{V}$
Coupled	Current Transfer Ratio (CTR)	1000			%	$1\text{mA } I_F, 2\text{V } V_{CE}$
	Collector-emitter Saturation Voltage $V_{CE(SAT)}$			1.2	V	$20\text{mA } I_F, 100\text{mA } I_C$
	Input to Output Isolation Voltage V_{ISO}	3750 5300			V_{RMS} V_{PK}	See note 1 See note 1
	Input-output Isolation Resistance R_{ISO}	5×10^{10}			Ω	$V_{IO} = 500\text{V}$ (note 1)
	Output Rise Time, tr Output Fall Time, tf		100 20	300 100	μs μs	$V_{CE} = 2\text{V}$, $I_C = 20\text{mA}, R_L = 100\Omega$

Note 1 Measured with input leads shorted together and output leads shorted together.

TAPING DIMENSIONS



Description	Symbol	Dimensions in mm (inches)
Tape wide	W	12 ± 0.3 (.47)
Pitch of sprocket holes	P_0	4 ± 0.1 (.15)
Distance of compartment	F	5.5 ± 0.1 (.217)
	P_2	2 ± 0.1 (.079)
Distance of compartment to compartment	P_1	8 ± 0.1 (.315)

CHARACTERISTIC CURVES

Fig.1 Forward Current vs. Ambient Temperature

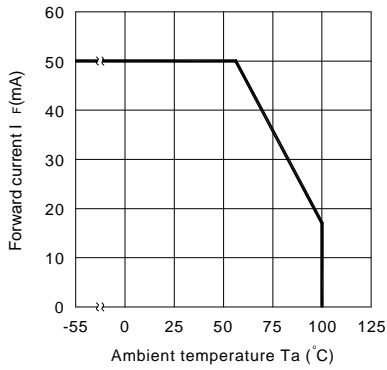


Fig.2 Collector Power Dissipation vs. Ambient Temperature

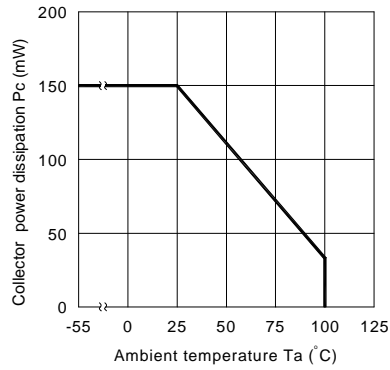


Fig.3 Collector-emitter saturation Voltage vs. Forward current

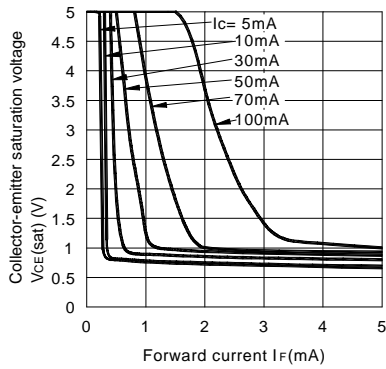


Fig.4 Forward Current vs. Forward Voltage

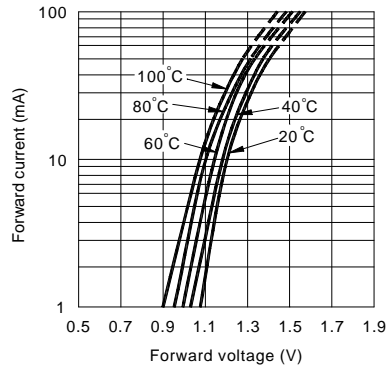


Fig.5 Current Transfer Ratio vs. Forward Current

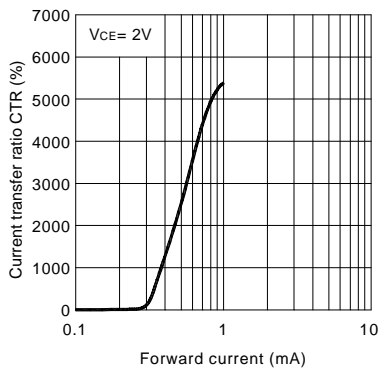
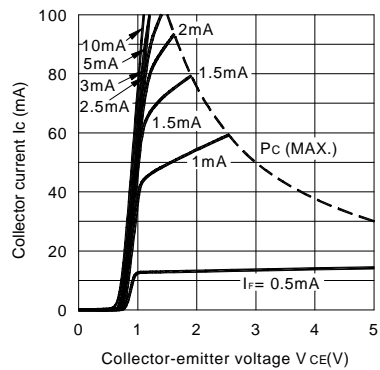


Fig.6 Collector Current vs. Collector-emitter Voltage



CHARACTERISTIC CURVES

Fig.7 Relative Current Transfer Ratio vs. Ambient Temperature

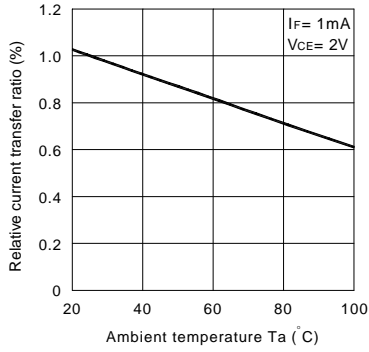


Fig.8 Collector-emitter Saturation Voltage vs. Ambient Temperature

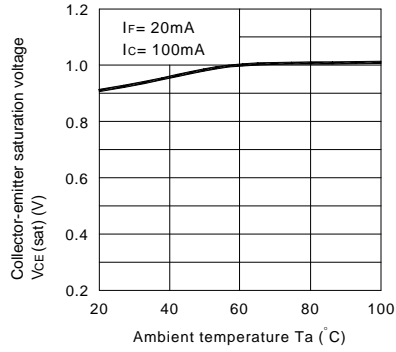


Fig.9 Collector Dark Current vs. Temperature

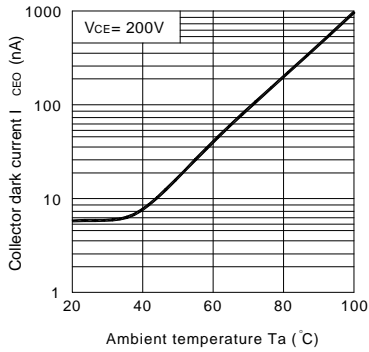


Fig.10 Response Time vs. Load Resistance

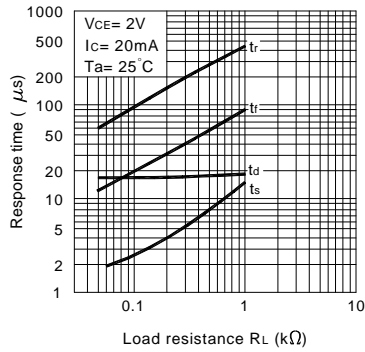
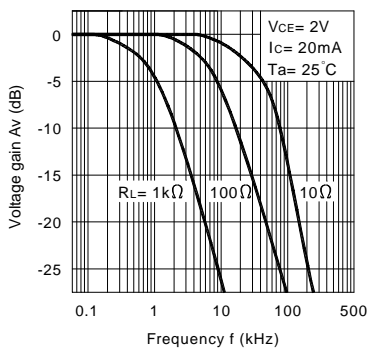
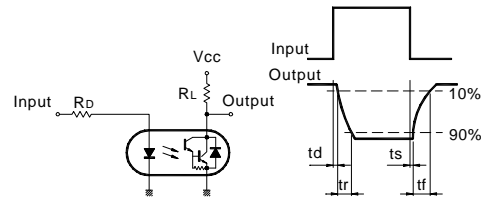


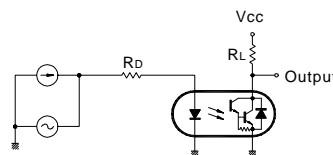
Fig.11 Frequency Response



Test Circuit for Response Time

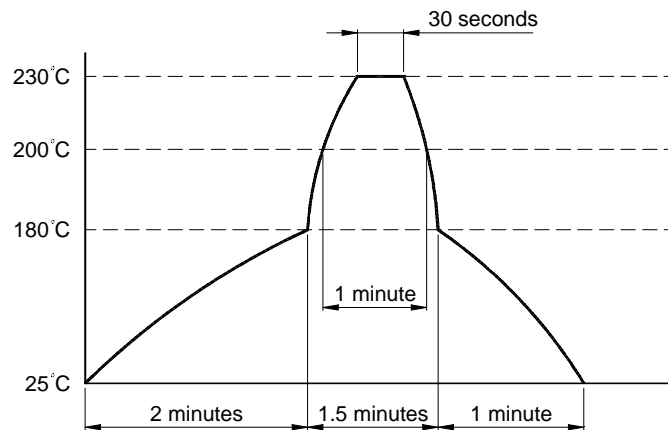


Test Circuit for Frequency Response



TEMPERATURE PROFILE OF SOLDERING REFLOW

- (1) One time soldering reflow is recommended within the condition of temperature and time profile shown below.



- (2) When using another soldering method such as infrared ray lamp, the temperature may rise partially in the mold of the device.
Keep the temperature on the package of the device within the condition of above (1).